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(12) **United States Design Patent**  
**Ito et al.**

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(54) **SUBSTRATE FOR SPECTROSCOPIC ANALYSIS**

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(51) **LOC (10) Cl.** ..... **24-02**

(52) **U.S. Cl.**  
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(58) **Field of Classification Search**

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422/69, 560-566; 435/288.1, 288.3, 289.1,  
435/283.1; 436/165

See application file for complete search history.

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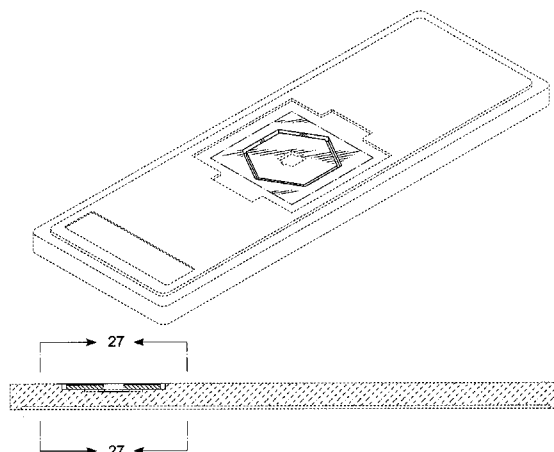
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Assistant Examiner — Mark Cavanna

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(57) **CLAIM**

The ornamental design for a substrate for spectroscopic analysis, as shown and described.



**DESCRIPTION**

FIG. 1 is a front view of a substrate for spectroscopic analysis of the first embodiment of our new design.

FIG. 2 is a rear view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 3 is a top plan view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 4 is a bottom view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 5 is a right side view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 6 is a left side view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 7 is a perspective of the substrate for spectroscopic analysis of FIG. 1.

FIG. 8 is a top plan view without the cover part of the substrate for spectroscopic analysis of FIG. 1.

FIG. 9 is a perspective view without the cover part of the substrate for spectroscopic analysis of FIG. 1.

FIG. 10 is a sectional view taken along the line 10-10 of the substrate for spectroscopic analysis of FIG. 3.

FIG. 11 is a sectional view taken along the line 11-11 of the substrate for spectroscopic analysis of FIG. 1.

FIG. 12 is a sectional view taken along the line 12-12 of the substrate for spectroscopic analysis of FIG. 8.

FIG. 13 is an enlarged sectional view taken along the line 13-13 of the substrate for spectroscopic analysis of FIG. 10.

FIG. 14 is a reference sectional view taken along the line 10-10 of the substrate for spectroscopic analysis of FIG. 3 in use, wherein the element is inserted in the concave part for element and the glass plate is set above the cover part.

FIG. 15 is a front view of a substrate for spectroscopic analysis of the second embodiment of our new design.

FIG. 16 is a rear view of the substrate for spectroscopic analysis of FIG. 15.

FIG. 17 is a top plan view of the substrate for spectroscopic analysis of FIG. 15.

FIG. 18 is a bottom view of the substrate for spectroscopic analysis of FIG. 15.

FIG. 19 is a right side view of the substrate for spectroscopic analysis of FIG. 15.

FIG. 20 is a left side view of the substrate for spectroscopic analysis of FIG. 15.

FIG. 21 is a perspective of the substrate for spectroscopic analysis of FIG. 15.

FIG. 22 is a top plan view without the cover part of the substrate for spectroscopic analysis of FIG. 15.

FIG. 23 is a perspective view without the cover part of the substrate for spectroscopic analysis of FIG. 15.

FIG. 24 is a sectional view taken along the line 24-24 of the substrate for spectroscopic analysis of FIG. 17.

FIG. 25 is a sectional view taken along the line 25-25 of the substrate for spectroscopic analysis of FIG. 15.

FIG. 26 is a sectional view taken along the line 26-26 of the substrate for spectroscopic analysis of FIG. 22.

FIG. 27 is an enlarged sectional view taken along the line 27-27 of the substrate for spectroscopic analysis of FIG. 24; and,

FIG. 28 is a reference sectional view taken along the line 24-24 of the substrate for spectroscopic analysis of FIG. 17 in use, wherein the element is inserted in the concave part for element and the glass plate is set above the cover part.

The dot and dashed lines define the bounds of the claimed design. The dot and dot lines show portions of the substrate for spectroscopic analysis that form no part of the claimed design.

The whole of the substrate for spectroscopic analysis of the first embodiment is transparent.

**1 Claim, 28 Drawing Sheets**

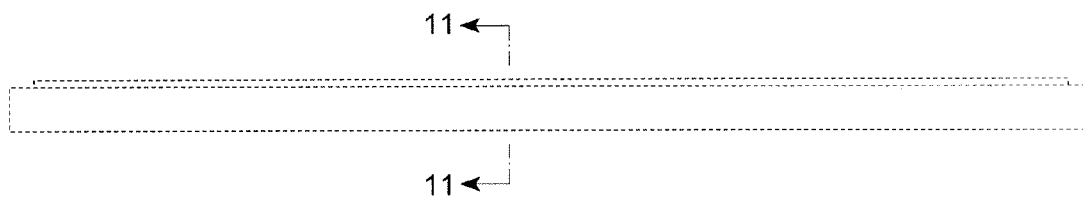


Fig.1



**Fig.2**

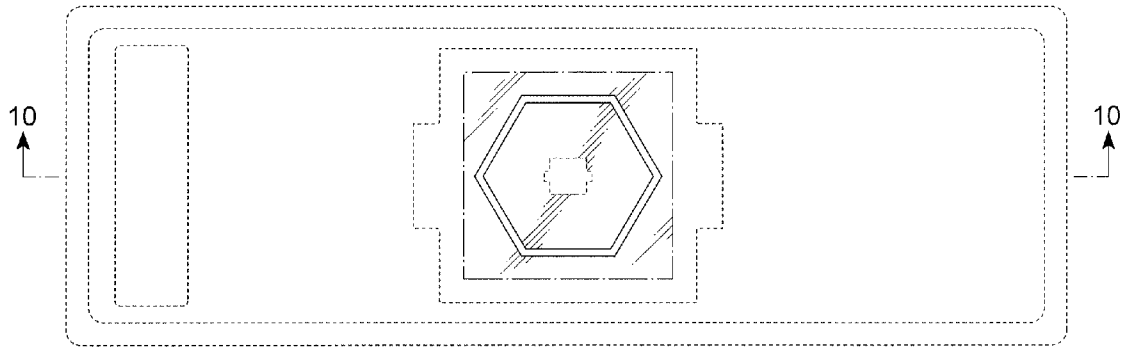


Fig.3

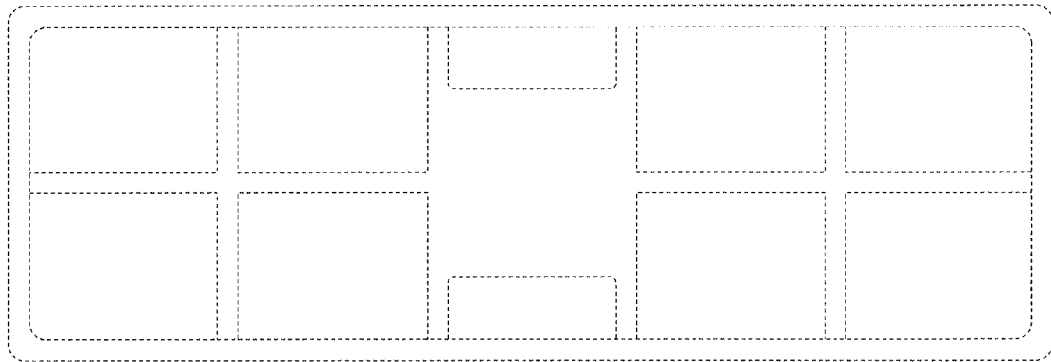
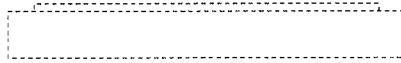


Fig.4



**Fig.5**



**Fig.6**



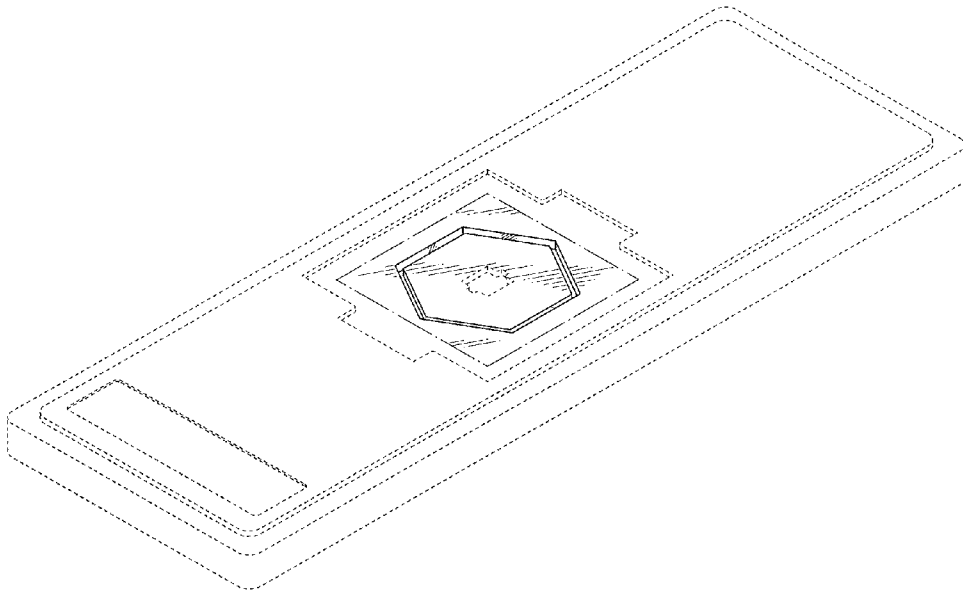


Fig.7

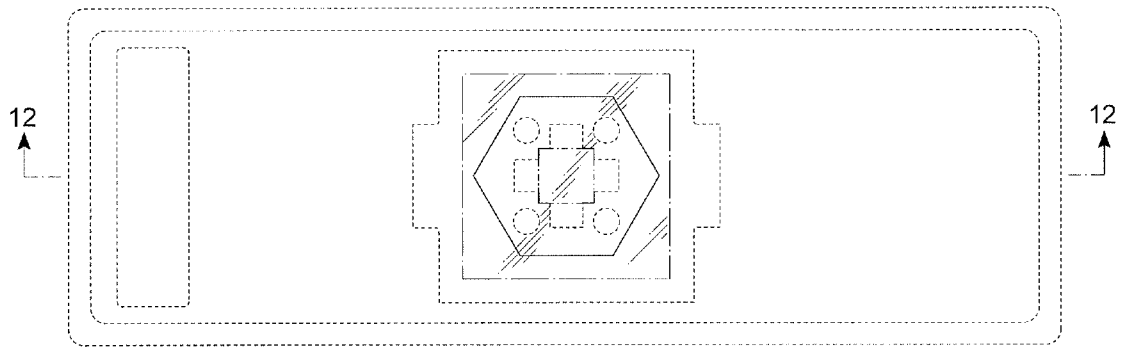


Fig.8

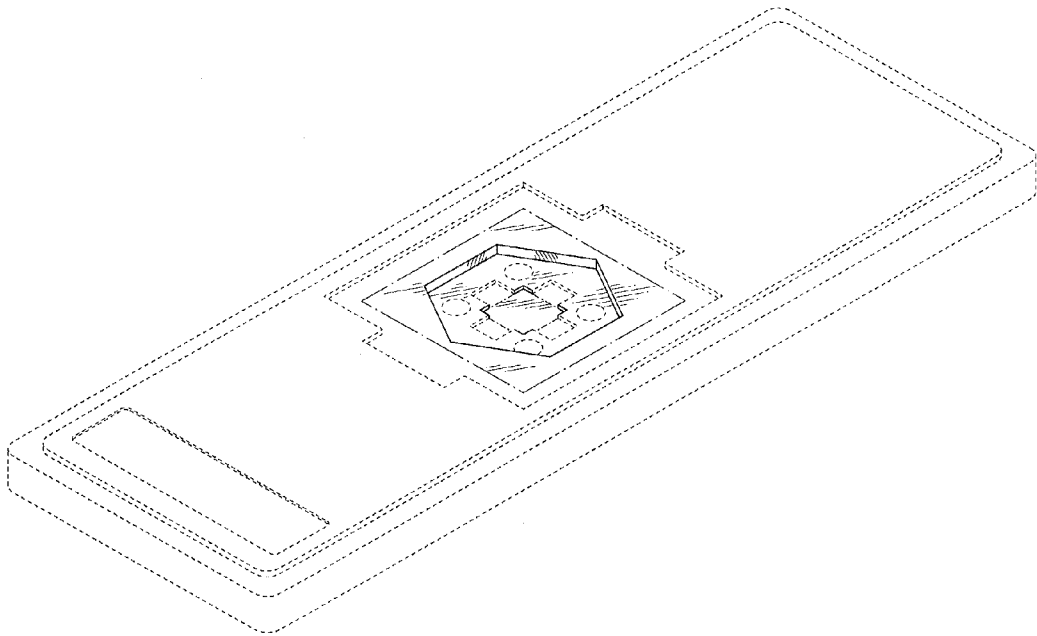


Fig.9

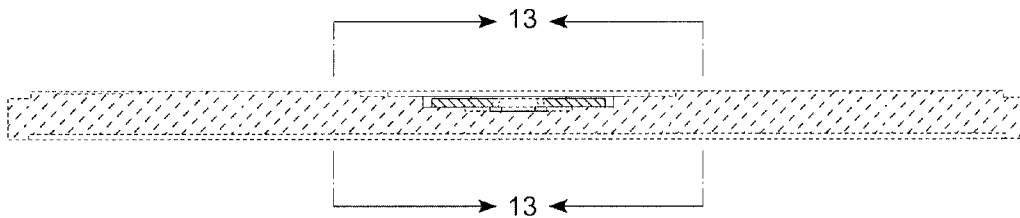


Fig.10



Fig. 11

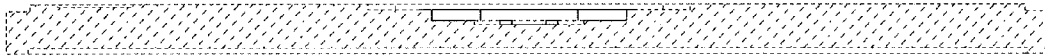


Fig.12

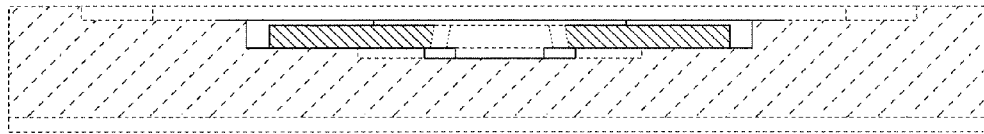


Fig.13

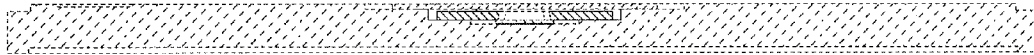


Fig.14





Fig.15



**Fig.16**



Fig.17

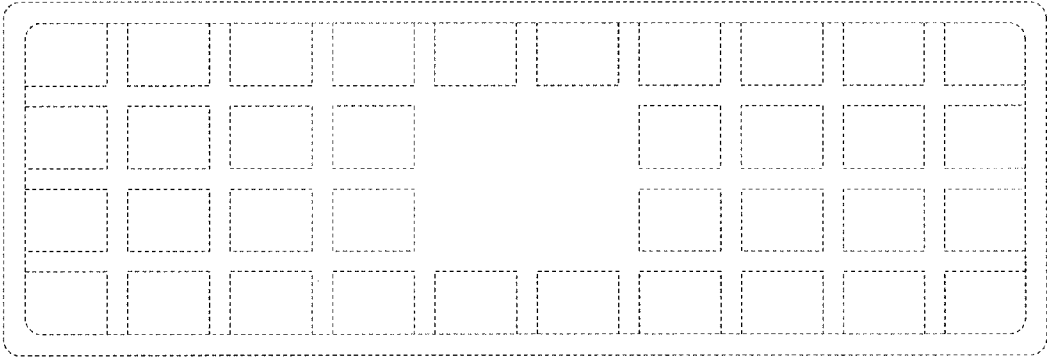


Fig.18



**Fig.19**



**Fig.20**

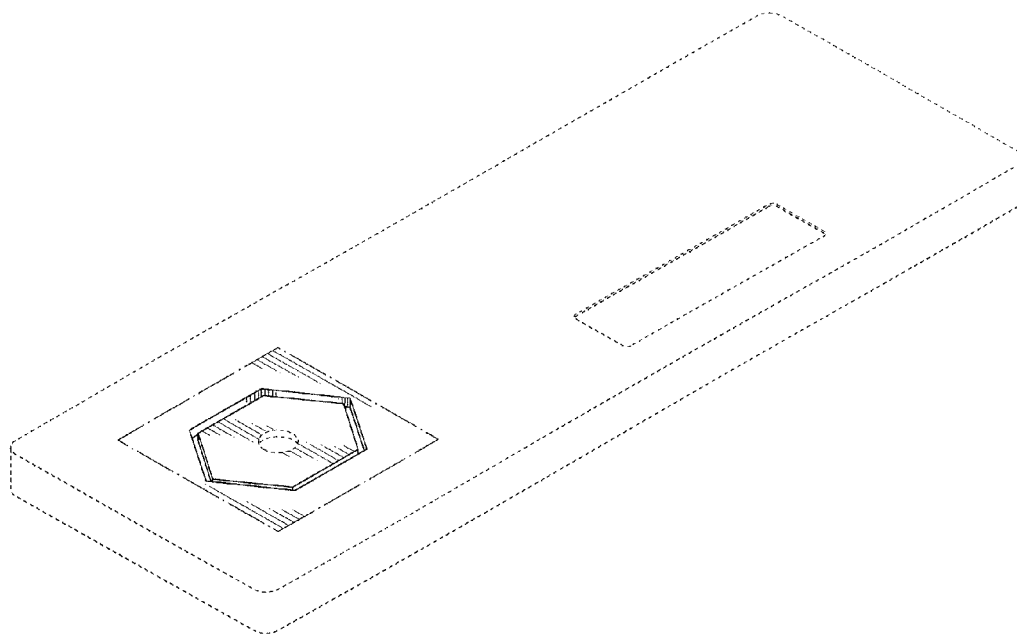


Fig.21

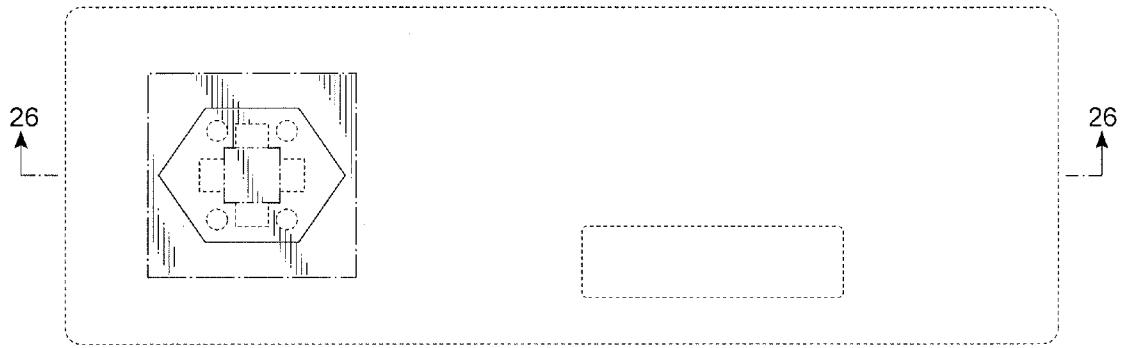


Fig.22



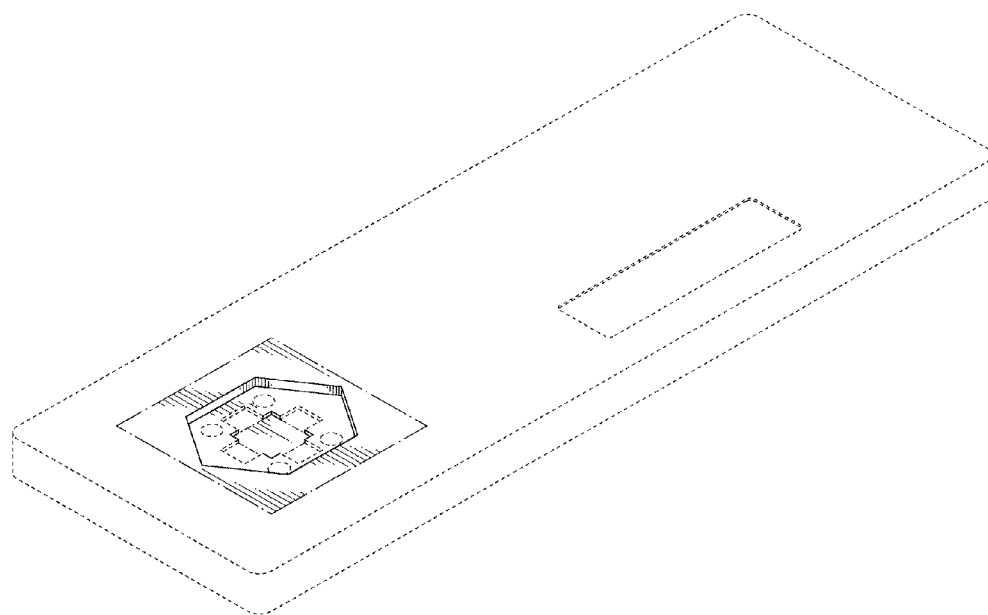


Fig.23

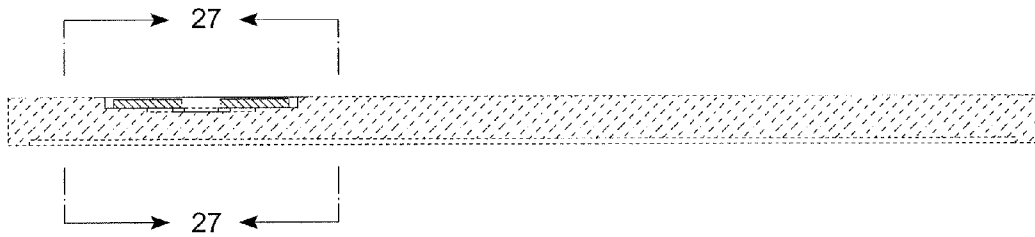


Fig.24

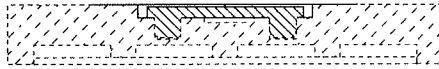


Fig.25



Fig.26

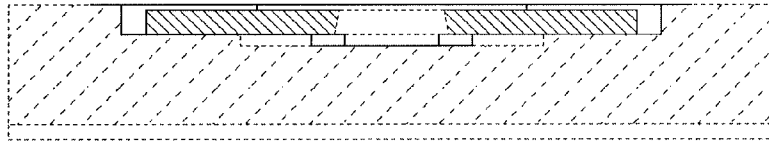


Fig.27

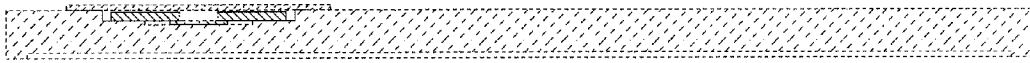


Fig.28